TUG 2018 TERADYNE USERS GROUP

Tuesday, May 8

Time					
9:00-9:30 am	WELCOME				
9:30-10:30 am	KEYNOTE ADDRESS				
10:30-11 am	VENDOR ADDRESS (2X 15 MINUTES)				VENDOR FAIR
11:00-11:30 am	BREAK				10:30am-5:00pm
SESSION 1	RF / WIRELESS	HIGH POWER DEVICE AND MODULE TEST	EXTENDING TEST SYSTEM CAPABILITY	MEMORY TEST	
11:30-12:00 pm	5G, Millimeter Wave Radios, and ATE (140)	Test Method To Detect Solder Voids in a Power Stack QFN Package (150)	UVS256 Temperature/Current Coefficient Measurements (149)	A Survey of Magnum's User-Installable Hooks (162)	
12:00-12:30 pm	Meeting the Test Challenges of 5G (75)	Achieving Low Cost Test on High Voltage High Current Industrial eFuse Devices. (143)	Power-up Slew Rate Control (21)	UFS Device Test Solutions Based On Magnum VU System (137)	
12:30-1:30 pm	LUNCH				
SESSION 2	RF / WIRELESS	HIGH POWER DEVICE AND MODULE TEST	EXTENDING TEST SYSTEM CAPABILITY	ENSURING PRODUCT QUALITY	
1:30-2:00 pm	mmWave(5G) Test Strategy (39)	Power Simulation for ETS88TH Load Board Design: Capacitance vs. Inductance (125)	Introduction of Extreme Pure Clock Solution based on LMK04828 (106)	Final Test Quality Improvement using Moving Dynamic Part Average Test Limits (64)	
2:00-2:30 pm	Challenges of Over-The-Air Testing at 60 GHz mmWave (8)	UHV DIB Design Challenges and Solutions (130)	Designing an External Instrument for Smart Phone Quick Charge Applications (128)	Automated Spike Checker (1)	
2:30-3:00 pm	Resolving Dual Tone Test Dilemmas Using an IQ Modulation Methodology (102)	Hardware Interface Design for Intelligent Power Module (IPM) Devices on ETS-88TH (111)	Achieving Force Accuracies Better Than the Published Spec. on VIs (153)	Advanced Datalog Tool for Live Data Analysis (12)	
3:00-3:30 pm	Expectation and Actual Result of Concurrent Test for SIP Device (117)	IGBT Testing Solutions and ESU Interface Solutions on ETS-88TH Platform (123)	A Generic DIB Diagnostics Solution (89)		
3:30-4:00 pm	BREAK				
SESSION 3	RF / WIRELESS	HIGH POWER DEVICE AND MODULE TEST	EXTENDING TEST SYSTEM CAPABILITY	MANUFACTURING TEST FLOW	
4:00-4:30 pm	Adaptive RF-DIB for ATE and Bench Reducing NRE-cost and Cycle Time (97)	Balanced Test Technique for Elimination of Setup Induced Errors in Sensitive High Current Output Measurement Using Eagle 364 Tester (86)	Waveform Analyzer Tool (76)	Panel Level Packaging (147)	
4:30-5:00 pm	J750-LitePoint TTR (13)		J750 Test Time Analysis With Only A Few Steps - The New Profiler (135)	What's The Best Probe Technology For My Device? (74)	
5:00-5:30 pm				Test Cost Optimization on Test Insertion Strategies (20)	
5:45-8:30 pm	TERADYNE PARTY				

Wednesday, May 9

Time					
9:00-10:00 am	**BUSINESS UPDATE & SEMICONDUCTOR TEST SOC** ENGINEERING UPDATE				
10:00-10:30 am	BREAK				VENDOR FAIR 10:00am-5:00pm
SESSION 4	AUTOMOTIVE	HIGH SPEED SERIAL	DIB DESIGN	TESTING FUNDAMENTALS	
10:30-11:00 am	Importance of Alarms in Automotive Test (26)	MIPI M-PHY Simulation with IBIS-AMI Model for UFS Signal Integrity Analysis (121)	Choosing the Right PCB Stackup Technology For Your Teradyne UltraFLEX Test Boards (99)	Leveraging the Power of the J750 DSIO for a Variety of Applications and Test Time Improvements (36)	
11:00-11:30 am	ETS-800 Safe Connection Analyzer (71)	Octal sites 1040MBps Eye Diagram Testing On UP1600 (14)	Electrical-Thermal Co-Simulation for Current Capacity in Fine Pitch DIB Design (116)	Virtual Parallel Site: How to Extend the J750 HD Capability To Use the DSIO In Parallel Mode For High Site Count Applications (141)	
11:30-12:00 pm	ETS800 SPU2112 Sharing Techniques for Applications Requiring >10A (4)	CDR and TTR Work-arounds on UltraPin1600 (16)	Novel DIB Layout Solution to Minimize Load Capacitance in pico-Amps Measurement (83)	Capacitor Measurement on J750HD for HDDPS, HDAPMU, HDCTO and HSD800 (65)	
12:00-1:00 pm	LUNCH				
SESSION 5	AUTOMOTIVE	HIGH SPEED SERIAL	LITEPOINT	TESTING FUNDAMENTALS	
1:00-1:30 pm	Accelerating Automotive Testing With UPD-64 (72)	Extending Walking Strobe and GigaDig Performance By Correcting DIB and Instrument Loss (161)	The Internet Of Things (IOT) Testing Matters (105)	Threshold Test Methods Summary on ETS800 (62)	
1:30-2:00 pm	Low Leakage Measurements: With or Without APU-12? (11)	US10G Solutions - Jitter Measure/ Functional Receive Above 10.7Gbps and Fast CMEM Unpacking (40)	MIPI RFFE Testing in Wireless Mobile Devices (108) MIPI RFFE Testing in Wireless Mobile Devices (108)	Power Integrity for ATE Boards Demystified (164)	
2:00-2:30 pm	Handy Temperature Monitoring For Eagle Test Systems Measurement Resources to Guarantee High Precision Measurement results to Spec (6)	Addressing 28Gbps SerDes Reference Clock Requirements By Low Jitter Clock Module (9)	GaN RF Device Trend and GaN Power Amplifier Test Challenges (110)	Digital Signal Processing vs. Background Processing (156)	
2:30-3:00 pm	The Study and Miscorrelation Correction of Signal Reflection on Nanosecond-scale Switching Characteristics Measurements (98)	56Gbps PAM4 and RF Together On UltraFLEX (145)	5G mmWave RF Testing (107)	Performance and Memory Advantages Of Using 64-bit IG-XL (136)	
3:00-3:30 pm	BREAK				
SESSION 6	EAGLE TUTORIAL	HIGH SPEED DIGITAL	TESTING FUNDAMENTALS	TESTING FUNDAMENTALS	
3:30-4:00 pm	Visual Studio 2015 Conversion Strategy for ETS Test Applications (146)	The Optimal Solution Of Accessing Device Using Register Mirror Method Through PA Module (95)	An IGXL Add-Ins for Limit-Sets Function (148)	Integration of Universal Robot into Performance Verification Test Process (87)	
4:00-4:30 pm		How to Deal with DUT Nondeterministic Behavior Using nWire PA (96)	An Analysis of Big Difference of SHMOO Between Different ATE (129)	How to Setup SSL Local Server License Without Unexpected Happening (119)	
4:30-5:00 pm			The Multi-Site Testing Solutions for Display PMIC Device (28)		
5:00-5:15 pm	**CLOSING REMARKS & PRESENTATION OF BEST PAPER AWARDS**				